

| | | | |
|-----------------------------------|---------------------------------------|--|-------------|
| Notice of References Cited | Application/Control No. 10/605,833 | Applicant(s)/Patent Under Reexamination HSIEH ET AL. | |
| | Examiner Elizabeth A. Rielley | Art Unit 2879 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|--------------------------|----------------|
| * | A | US-6,100,545 | 08-2000 | Chiyo et al. | 257/98 |
| * | B | US-2003/0062519 | 04-2003 | Yamazaki et al. | 257/40 |
| * | C | US-2001/0028062 | 10-2001 | Uemura et al. | 257/79 |
| * | D | US-2002/0179914 | 12-2002 | Sheu, Jinn-Kong | 257/90 |
| * | E | US-5,670,798 | 09-1997 | Schetzina, Jan Frederick | 257/96 |
| * | F | US-2003/0129447 | 07-2003 | Madathil et al. | 428/690 |
| * | G | US-6,768,855 | 07-2004 | Bakke et al. | 385/129 |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.